

# Ab initio calculations of optoelectronic properties of antimony sulfide nano-thin film for solar cell applications

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## ABSTRACT

Antimony sulfide (Sb<sub>2</sub>S<sub>3</sub>) micro thin-film have been received great interest as an absorbing layer for solar cell technology. In this study, to explore its further potential, electronic and optical properties of Sb<sub>2</sub>S<sub>3</sub> simulated nano-thin film are investigated by the first-principles approach. To do so, the highly accurate full-potential linearized augmented plane wave (FP-LAPW) method framed within density functional theory (DFT) as implemented in the WIEN2k package is employed. The films are simulated in the [0 0 1] direction using the supercell method with a vacuum along z-direction so that slab and periodic images can be treated independently. From our calculations, indirect band gap energy values of Sb<sub>2</sub>S<sub>3</sub> for various slabs are found to be 0.568, 0.596 and 0.609 eV for 1, 2 and 4 slabs respectively. Moreover, optical properties comprising of real and imaginary parts of the complex dielectric function, absorption coefficient, refractive index are also investigated to understand the optical behavior of the obtained simulated Sb<sub>2</sub>S<sub>3</sub> thin films. From the analysis of their optical properties, it is clearly seen that Sb<sub>2</sub>S<sub>3</sub> thin films have good values for optical absorption parameters in the visible and ultraviolet wavelength range, showing the aptness of antimony sulphide thin films for versatile optoelectronic applications as a base material.

## Introduction

The worldwide demand for high performance and low-cost photovoltaic devices is becoming more eminent due to the extensive usage of electricity-consuming devices as a result of the rapid growth of the population [1,2]. The dire requirement for low-cost and efficient optoelectronic devices has led to an increasing focus on a range of different source materials along with the development of a method to characterize these materials [3]. CdTe and Cu(In, Ga)(S, Se) (CIGS) with 30% solar conversion efficiency are leading candidates for light-absorbing materials used in thin-film photovoltaics [4–6]. Nevertheless, the toxicity and restrictions on the usage of Cd being heavy metal and limited supply of In and Te urge for other alternative absorber materials for large-area manufacturing compatibility [7–10], and to reduce the \$W<sup>-1</sup> price using low-cost materials. To this point, Sb<sub>2</sub>S<sub>3</sub> semiconductor material has received great attention as a promising candidate for photovoltaic applications, owing to its excellent electronic and optical properties, environmentally friendly constituents, earth-abundant, stable and simple phase with low melting point [2,11–13].

Sb<sub>2</sub>S<sub>3</sub> is a layered semiconducting material with an orthorhombic

crystal structure containing 20 atoms per unit cell [14] and is considered to be useful as an absorbing layer in solar cells because of its potential optical properties [15,16]. The absorption coefficients and optical band gap values of Sb<sub>2</sub>S<sub>3</sub> macro thin films are reported in the range of cm<sup>-1</sup> and 1.6 – 1.8eV [17,18]. According to an experimental study done by Itzhak et al., the Sb<sub>2</sub>S<sub>3</sub> thin films that have thicknesses of 10–50 nm have shown great potential for an absorber layer in semiconductor-sensitized solar cell applications [17] due to their high absorption coefficient than other material used in thin-film solar cells. This is one of our motivations to investigate the Sb<sub>2</sub>S<sub>3</sub> material at nanoscale level [19]. Conversely, the physical properties of nanoscale thin films have also been shown strong dependence on the thickness of the films due to quantum confinement effect or quantum size effects [20,21]. Therefore, investigations, at different length scale, are found in the literature on the thin films of Sb<sub>2</sub>S<sub>3</sub> to evaluate its impact on the physical properties [22–26].

Tuning of the thickness in semiconductors thin films can lead to changing in their electronic and optical properties due to the confinement of the electrons movement [27]. A recent study on Sb<sub>2</sub>S<sub>3</sub> thin film, pertaining to the thicknesses from 77 to 206 nm, is reported in the

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literature which clearly shows effect of thickness on the optoelectronic properties, indicating the existence of quantum size effect [28]. It is well known that electronic and optical properties of semiconductor materials play an important role in determining their optoelectronic behavior [29].

Usually, density functional theory (DFT) based on GGA and LDA first principles approaches being used for investigating the electronic and optical properties of semiconductor materials [30,31]. First-principles calculations mean an approach of doing calculations that rely on well-established and fundamental laws of science that do not involve any fitting techniques, special models or suppositions. Although GW like methods is also available, they are expensive and impractical for thin-film calculations of semiconductors [32–34].

Here, we use Engel-Vosko approach of exchange correlation potential as it is simple but reproduces usually nice results for optoelectronics properties. Several theoretical works on a thin-film study concerning the effect of thickness for the different materials have been done [35–39], including studies on  $\text{Sb}_2\text{S}_3$  [14,40–44], to the best of our knowledge investigations of electronic and optical properties with highly accurate all-electron full-potential linearized augmented plane wave (FP-LAPW) on  $\text{Sb}_2\text{S}_3$  thin film for different thicknesses, have not been explored yet, due to its complex and disordered structure. In this paper, electronic and optical properties of  $\text{Sb}_2\text{S}_3$  (001) thin films for different thicknesses were calculated within Engel Vosko generalized gradient approximation (EV-GGA) [45].

### Computational details

Electronic and optical properties of  $\text{Sb}_2\text{S}_3$  thin films with different thicknesses are performed via first-principles full-potential linearized augmented-plane-wave (FP-LAPW) method within the DFT scheme as employed in WIEN2k program [46]. Using slab geometry supercell, the thin films are formed by using optimized lattice constants in (001) direction using  $(1 \times 1)$  cell for various thicknesses (1–8 slabs). A slab is represented by optimized bulk of orthorhombic  $\text{Sb}_2\text{S}_3$  ( $\alpha = \beta = \gamma = 90^\circ$ ,  $a = 1.1646$  nm,  $b = 0.3953$  nm and  $c = 1.1587$  nm) as illustrated in Fig. 1. A large vacuum of 3 nm along z-plane was considered to avoid inter-layer interaction.

Table 1 shows a list of thicknesses for different numbers of layers (from 1 to 8 slabs) for  $\text{Sb}_2\text{S}_3$  (001) thin films. To calculate the total energy of the system, EV-GGA approximation was used as the exchange–correlation potential. The EV-GGA potential has been justified to provide quite accurate band gaps for various semiconducting materials including  $\text{Sb}_2\text{S}_3$  [40,42]. The wave functions are expanded in spherical harmonics inside the Muffin-Tin radius ( $R_{\text{MT}}$ ) centered around each nucleus [47]. To ensure the accuracy of the calculations, the  $R_{\text{MT}}K_{\text{max}}$  was set to be 7. Other parameters included in the calculation are used as  $G_{\text{max}} = 7$  and  $I_{\text{max}} = 12$ , where  $G_{\text{max}}$  is the maximum expansion magnitude of the basis function and  $I_{\text{max}}$  is the maximum expansion magnitude of the wavefunctions in spherical harmonics inside the muffin tins (MTs). These parameters are selected to determine the extent of the matrix. Three hundred k-points in the first Brillouin zone were adopted in the calculations (250 points in the irreducible part of the surface Brillouin zone). The iterations were stopped when the difference of total energy was less than 0.00001 Ry between the steps, taken as a convergence criterion.

### Results and discussion

#### Electronic properties

The electronic properties are concerned with band structure calculations and density of states (DOS). For a better understanding of the thickness dependence electronic band structure, we analyze the electronic band structure of  $\text{Sb}_2\text{S}_3$  (001) film with respect to the number of slabs. The k path selected along high symmetry point in the first

Brillouin zone is  $Y \rightarrow \Gamma \rightarrow S \rightarrow \Gamma$ . The band structure plots of  $\text{Sb}_2\text{S}_3$  in bulk form and film from 1 to 8 slabs with EV-GGA along selected high symmetry directions in the Brillouin zone are presented in Fig. 2. The Fermi energy at the bottom of conduction band is defined to be zero energy (0 eV). EV-GGA functionals are selected in our calculations, it provides good predictions on bandgap value for both bulk and surface states of numerous semiconductor materials than bare GGA [48–50]. Lack of study on 2D materials using this exchange–correlation functional motivated us to use it in our present calculations. It is evident from Fig. 2 that  $\text{Sb}_2\text{S}_3$  slabs exhibit an indirect bandgap with valence band maximum lying between S and  $\Gamma$  and conduction band minimum at  $\Gamma$ -symmetry point respectively. The indirect bandgap value of bulk  $\text{Sb}_2\text{S}_3$  with EV-GGA functionals without spin–orbit coupling was found to be 1.661 eV and this value is in good agreement with previous theoretical work and experimental measurement of 1.1–2.8 eV [13,14,51]. However, our calculated values of indirect energy gaps of  $\text{Sb}_2\text{S}_3$  slabs were found to be 0.568 and 0.596 eV for slab 1 and 2 respectively and this trend is consistent with the experimental work studied by Mane et al. [28] where the bandgap value reduced when the thickness increased. This effect demonstrates the quantum size effect of holes and electrons in  $\text{Sb}_2\text{S}_3$ . This change of bandgap becomes evident that thickness of films has an effect on material physical properties. On the other hand, the magnitude of the energy band gap remains the same when the film is more than 3 slabs. Although the energy band gap values are the same when the film thickness is more than 3 slabs the number of bands in both conduction and valence band enhanced as the thickness of  $\text{Sb}_2\text{S}_3$  (001) films increases and this trend is in quite agreement with previous thin-film studies [52–56]. However, it is clear from Fig. 2 that the indirect energy gap of  $\text{Sb}_2\text{S}_3$  slabs reduced by 1 eV with respect to its bulk counterpart. The reason for lowering bandgap energy in  $\text{Sb}_2\text{S}_3$  films when compared with the bulk form is due to quantum confinement effect that had been discussed in detail and confirmed in various other studies previously [57–60] and our previous study of nanowire [61]. To further probe the nature of the energy gap, we have also studied the total density of states (DOS) of  $\text{Sb}_2\text{S}_3$  films with different slabs within EV-GGA. Fig. 3 shows the graph of total DOS. From the total DOS plots, the peaks of the density of states in the valence band region increase significantly near the Fermi level in number while in the conduction band region the increase starts at 1.5 eV. The increment in total DOS corresponds to the increase in number of atoms and electrons in the films. Therefore, it is possible to exploit the quantum confinement effect to tune the electronic properties in  $\text{Sb}_2\text{S}_3$  films.

#### Optical properties

This part provides several optical parameters of  $\text{Sb}_2\text{S}_3$  thin films which are determined for the first time by highly accurate first-principles all-electron full-potential linearized augmented plane wave method. Optical parameters of material normally explain the behavior of the material when exposed to electromagnetic radiation and they also help in predicting band structure configuration. The understanding of the optical behavior of material is essential to estimate its usefulness and applicability for optoelectronic applications [62]. Optical behavior is strongly associated with electronic structure [29]. As observed in the electronic band structure analysis, the geometry of the electronic structure for  $\text{Sb}_2\text{S}_3$  thin film changed with film thickness. Several experimental studies have also shown previously that the optical properties of  $\text{Sb}_2\text{S}_3$  thin film are dependent upon the thickness of the film. However, to the best of our knowledge theoretical investigation on  $\text{Sb}_2\text{S}_3$  thin films has not been reported yet on optical properties. In order to describe the said parameters quantitatively, it is essential to evaluate dielectric function. Dielectric function is the ratio of the permittivity of a material to the permittivity of free space, whereas permittivity is the measure of the resistance of a material when an electric field is induced in a material. All the dielectric materials are insulator

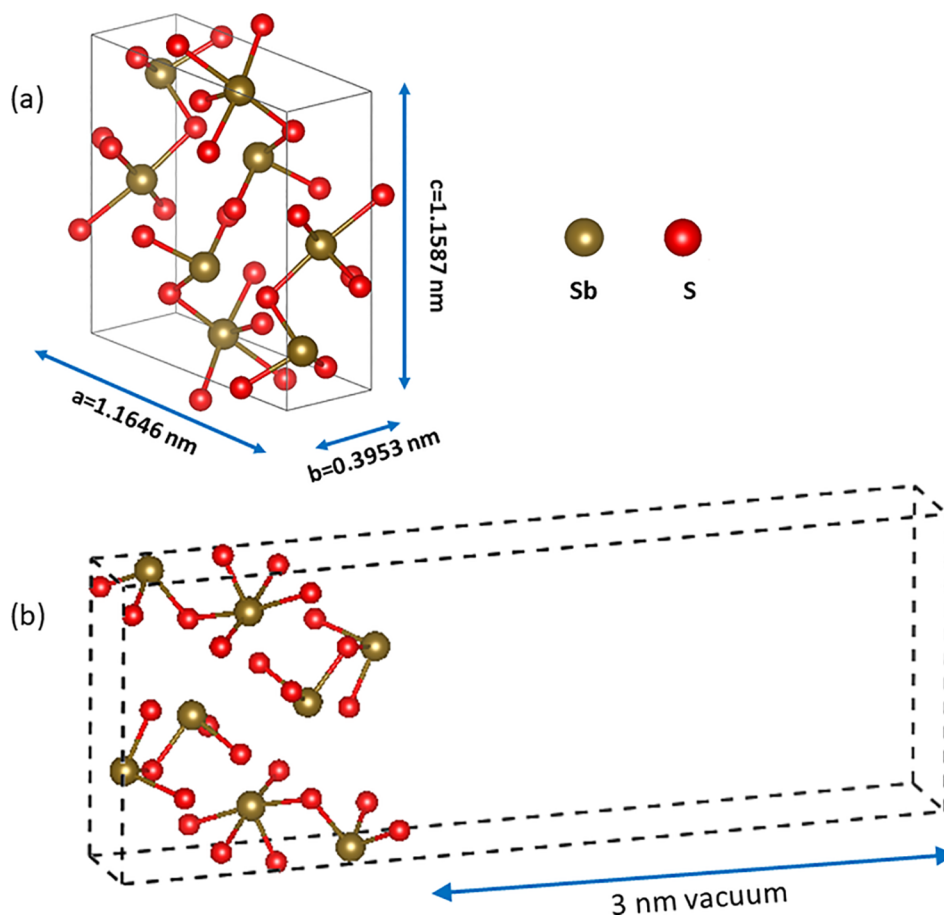


Fig. 1. Crystal structure of optimized (a) unit cell of the  $\text{Sb}_2\text{S}_3$  and (b) 1 slab of  $\text{Sb}_2\text{S}_3$  (001) thin film with 3 nm vacuum.

Table 1

Thicknesses for a different number of layers (from 1 to 8 slabs) for  $\text{Sb}_2\text{S}_3$  (001) thin films.

Number of slabs	Thickness(nm)
1	1.16
2	2.31
4	4.63
6	6.95
8	9.27

but all the insulators are not dielectric [63]. The dielectric function consists of real ( $\varepsilon_1(\omega)$ ) and imaginary part ( $\varepsilon_2(\omega)$ ). It is represented as follows:

$$\varepsilon(\omega) = \varepsilon_1(\omega) + i\varepsilon_2(\omega) \quad (1)$$

where  $\varepsilon_1(\omega)$  is real part and  $\varepsilon_2(\omega)$  is an imaginary part of the dielectric function. Physical properties and band structure rely strongly on  $\varepsilon(\omega)$ .

As mentioned, we analyzed the optical properties based on EV-GGA functionals. From the knowledge of electronic band structure of a solid, the imaginary part of the dielectric function,  $\varepsilon_2(\omega)$  can be calculated from Kubo–Greenwood equation as shown in Eq. (2):

$$\varepsilon_2(\omega) = \frac{2\pi e^2}{\Omega \varepsilon_0} |\langle \psi_k^c | \hat{u} \times \vec{r} | \psi_k^v \rangle| \delta(E_k^c - (E_k^v + E)) \quad (2)$$

Once we know the imaginary part, the real part,  $\varepsilon_1(\omega)$  can be obtained from the Kramers–Kronig relations in Eq. (3).

The real part of the dielectric function gives information about the refractive index of any material under investigation while imaginary part explains the absorption of light. The calculated imaginary ( $\varepsilon_2$ ) and the real ( $\varepsilon_1$ ) parts of the dielectric functions as a function of the photon

energy are shown in Fig. 4(a)–(b) in the energy range of 0–20 eV. Although it has been established that  $\text{Sb}_2\text{S}_3$  semiconductor has orthorhombic symmetry and this symmetry has three independent components of dielectric function, for this work we only consider polarization along [001] direction.

$$\varepsilon_1(\omega) = 1 + \left(\frac{2}{\pi}\right) \int_0^\infty d\omega' \frac{\omega'^2 \varepsilon_2(\omega')}{\omega'^2 - \omega^2} \quad (3)$$

The static dielectric constant,  $\varepsilon_1(0)$  is the real part of dielectric constant at zero energy. These parameters were analyzed for  $\text{Sb}_2\text{S}_3$  thin films as can be seen in Fig. 4(a). Table 2 shows an illustration of the static dielectric constant for different slabs. From the results, it is noticed that the value of static dielectric constant increases as the thin film thickness increases. Conversely, these are also important parameters that could be also used to obtain the energy band gap values of  $\text{Sb}_2\text{S}_3$  thin films via Penn Model relation [64]. Using plasma energy  $\hbar\omega_p$  and the value of  $\varepsilon_1(0)$ , the value of the energy gap of the title material can be calculated by using Penn expression. Interestingly, it was also observed that  $\text{Sb}_2\text{S}_3$  thin films possesses plasmonic behavior when the thickness of the film is greater than one slab (1 slab). This negative behavior of real part (plasmonic behavior) is another exciting feature to make  $\text{Sb}_2\text{S}_3$  thin film suitable for many applications [65–67].

It has been established that the imaginary part of dielectric function is directly connected with the energy band structure. The edge of optical absorption (first critical point) occurs at about 0.562, 0.589, 0.608, 0.607, 0.606 eV for 1, 2, 4, 6 and 8 slabs. Hence, the calculated imaginary part of the dielectric function shows that the first critical peak point is related to the transition from the valence to the conduction band states corresponding to the fundamental bandgap. The results of imaginary part of dielectric function indicate that  $\text{Sb}_2\text{S}_3$  thin films have

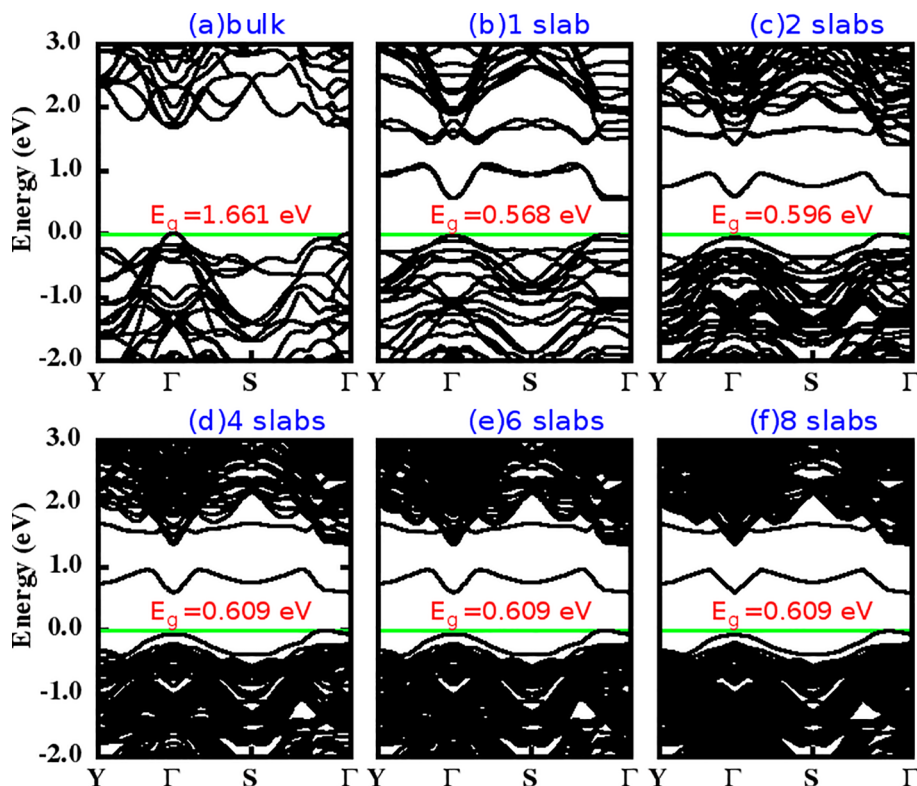


Fig. 2. Band structures of the bulk  $\text{Sb}_2\text{S}_3$  (a) and  $\text{Sb}_2\text{S}_3$  (001) thin films with five different thicknesses: 1 slab (b), 2 slabs (c), 3 slabs (d), 4 slabs (e), 5 slabs(f).

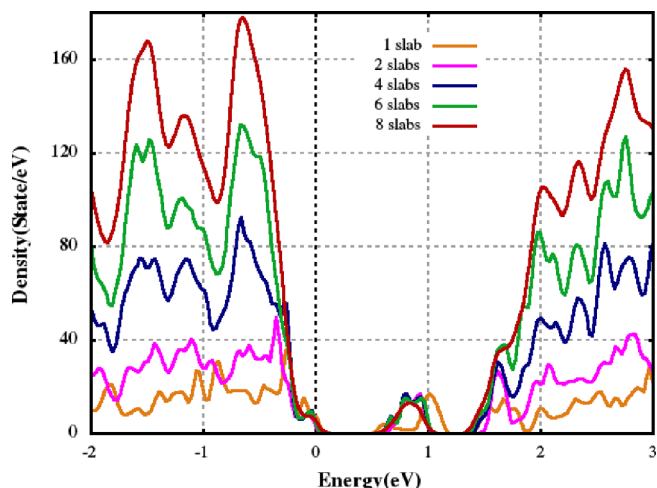


Fig. 3. Total density of states of the  $\text{Sb}_2\text{S}_3$  (001) thin films with various thicknesses.

shown strong absorption in the visible light frequency, which depicts its suitability for optoelectronic applications. Apparently, due to crystallinity of the films, the optical absorption increases with the increase in the film thickness.

$$\alpha(\omega) = \frac{\omega}{c} \sqrt{2(\sqrt{\varepsilon_1^2(\omega) + \varepsilon_2^2(\omega)} - \varepsilon_1(\omega))} \quad (4)$$

$$n(\omega) = \sqrt{\left( \frac{\sqrt{\varepsilon_1^2(\omega) + \varepsilon_2^2(\omega)} + \varepsilon_1(\omega)}{2} \right)} \quad (5)$$

Using the knowledge of the complex dielectric constant, other optical parameters such as absorption coefficient,  $\alpha(\omega)$  and refractive index,  $n(\omega)$  can be determined. Fig. 4(c)–(d) shows the energy dependence of the absorption coefficient and refractive index. For

photovoltaic applications, it is important to use a material with a suitable bandgap having large absorption coefficient [68]. When light rays strike the surface of a material, some part of its energy is reflected while some are transferred to the surface of the material. This transfer of energy to the surface is called absorption of light and it is represented in terms of absorption coefficient  $\alpha(\omega)$ . The graph of the absorption coefficient as a function of photon energy is presented in Fig. 4(c). From this graph, it is clear that  $\text{Sb}_2\text{S}_3$  thin films shown good absorption coefficient values in the visible and ultraviolet wavelength range. Since  $\text{Sb}_2\text{S}_3$  thin films show good absorption coefficients in the visible and ultraviolet-wavelength range for all thicknesses, it is anticipated that these films can be used as optoelectronic devices. The curves of refractive index  $n(\omega)$  in Fig. 4(d) are similar to the real part of dielectric function  $\varepsilon_1(\omega)$  which is also in accordance with the established theory [69]. The values of static refraction index for different thickness of  $\text{Sb}_2\text{S}_3$  (001) thin-film are given in Table 2. From the graph, we observed that the values of  $n(\omega)$  in  $\text{Sb}_2\text{S}_3$  (001) thin films are also influenced by the film thickness.

## Conclusion

In summary, the electronic and optical properties of  $\text{Sb}_2\text{S}_3$  nano-thin films were studied by a highly accurate full-potential linearized augmented plane wave (FP-LAPW) approach based on DFT within EV-GGA exchange–correlation. The calculated values of indirect band gaps of  $\text{Sb}_2\text{S}_3$  were found to be 0.568, 0.596 and 0.609 eV for 1, 2 and 4 slabs respectively. The bandgap values were found to be reduced when the thickness is increased. Although experimental research work at this scale is rare, this trend is consistent with experimental work where available. Optical properties including real and imaginary parts of the complex dielectric function, absorption coefficient, the refractive index were also investigated to understand the optical behavior of  $\text{Sb}_2\text{S}_3$  nano-thin films. From the analysis of optical properties, it was clearly shown that  $\text{Sb}_2\text{S}_3$  thin films have good optical absorption in the visible and ultraviolet wavelength range, it is, therefore, anticipated that these

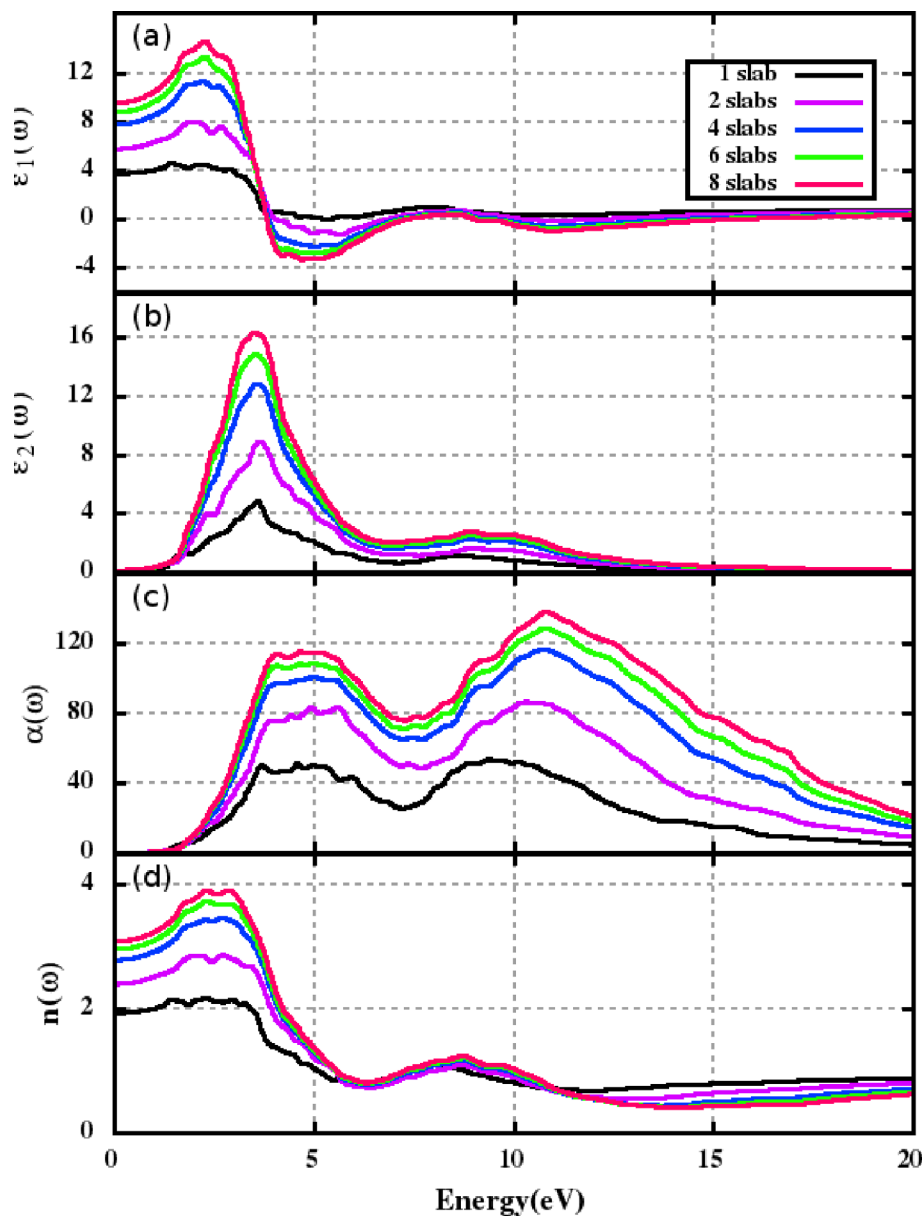


Fig. 4. (a) Real and (b) imaginary part of dielectric functions, (c) absorption coefficient and (d) refractive index for different slabs of  $Sb_2S_3$  (0 0 1) thin films shown.

Table 2

Static dielectric,  $\epsilon_1(0)$  and Static refractive index,  $n(0)$  of  $Sb_2S_3$  (0 0 1) thin films for different slabs.

Thin film	Static dielectric, $\epsilon_1(0)$	Static refractive index, $n(0)$
Number of slabs	1	1.94
	2	2.41
	4	2.80
	6	2.97
	8	3.10

films can be used for versatile optoelectronic devices. However further investigations at experimental and theoretical levels with different techniques are recommended.

**Declaration of Competing Interest**

The authors declare that they have no known competing financial interests or personal relationships that could have appeared to influence the work reported in this paper.

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